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FDS6676AS

30V N-Channel PowerTrench® SyncFET™

General Description

The FDS6676AS is designed to replace a single SO-8 MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\text{DS(ON)}}$ and low gate charge. The FDS6676AS includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

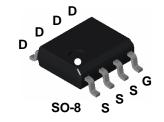
Applications

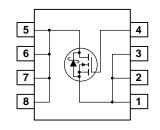
- DC/DC converter
- · Low side notebook



Features

- 14.5 A, 30 V. $R_{DS(ON)}$ max= 6.0 m Ω @ V_{GS} = 10 V $R_{DS(ON)}$ max= 7.25 m Ω @ V_{GS} = 4.5 V
- Includes SyncFET Schottky body diode
- Low gate charge (45nC typical)
- High performance trench technology for extremely low R_{DS(ON)} and fast switching
- High power and current handling capability
- RoHS Compliant





Absolute Maximum Ratings T_{A=25}°C un

T_A=25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|--|-----------|-------------|-------|
| V _{DSS} | Drain-Source Voltage | | 30 | V |
| V _{GSS} | Gate-Source Voltage | | ±20 | V |
| I _D | Drain Current - Continuous | (Note 1a) | 14.5 | А |
| | – Pulsed | | 50 | |
| P _D | Power Dissipation for Single Operation | (Note 1a) | 2.5 | W |
| | | (Note 1b) | 1.2 | |
| | | (Note 1c) | 1 | |
| T _J , T _{STG} | Operating and Storage Junction Temperatu | re Range | -55 to +150 | °C |

Thermal Characteristics

| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | (Note 1a) | 50 | °C/W |
|-----------------|---|-----------|----|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | (Note 1) | 25 | |

Package Marking and Ordering Information

| Device Marking | Device | Reel Size | Tape width | Quantity |
|----------------|-----------|-----------|------------|------------|
| FDS6676AS | FDS6676AS | 13" | 12mm | 2500 units |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|---|---|--|-----|-------------------|--------------------|-------|
| Off Char | acteristics | | I. | · | · | · |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, \qquad I_D = 1 \text{ mA}$ | 30 | | | V |
| <u>ΔBV_{DSS}</u> ΔT _J | Breakdown Voltage Temperature Coefficient | I_D = 10 mA, Referenced to 25°C | | 20 | | mV/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$ | | | 500 | μΑ |
| I_{GSS} | Gate-Body Leakage | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ | | | ±100 | nA |
| On Char | acteristics (Note 2) | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$ | 1 | 1.5 | 3 | V |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate Threshold Voltage Temperature Coefficient | I_D = 10 mA, Referenced to 25°C | | -4 | | mV/°C |
| R _{DS(on)} | Static Drain–Source On–Resistance | $ \begin{vmatrix} V_{GS} = 10 \text{ V}, & I_D = 14.5 \text{ A} \\ V_{GS} = 4.5 \text{ V}, & I_D = 13.2 \text{ A} \\ V_{GS} = 10 \text{ V}, I_D = 14.5 \text{ A}, T_J = 125 ^{\circ} \text{C} \\ \end{vmatrix} $ | | 4.5 5.9 6.7 | 6.0 7.25 8.5 | mΩ |
| I _{D(on)} | On–State Drain Current | $V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$ | 50 | | | Α |
| g _{FS} | Forward Transconductance | $V_{DS} = 10 \text{ V}, \qquad I_{D} = 14.5 \text{ A}$ | | 66 | | S |
| Dynamic | Characteristics | | | | | |
| C _{iss} | Input Capacitance | $V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ | | 2510 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 710 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 270 | | pF |
| R_G | Gate Resistance | $V_{GS} = 15 \text{ mV}, \qquad f = 1.0 \text{ MHz}$ | | 1.6 | 2.8 | Ω |
| Switchin | g Characteristics (Note 2) | | | | | |
| t _{d(on)} | Turn-On Delay Time | $V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$ | | 10 | 20 | ns |
| t _r | Turn-On Rise Time | $V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$ | | 12 | 22 | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 43 | 69 | ns |
| t _f | Turn-Off Fall Time | | | 29 | 46 | ns |
| t _{d(on)} | Turn-On Delay Time | $V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$ | | 17 | 31 | ns |
| t _r | Turn-On Rise Time | $V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$ | | 22 | 35 | ns |
| $t_{\text{d(off)}}$ | Turn-Off Delay Time | | | 34 | 54 | ns |
| t _f | Turn-Off Fall Time | | | 29 | 46 | ns |
| Q _{g(TOT)} | Total Gate Charge at Vgs=10V | | | 45 | 63 | nC |
| Q_g | Total Gate Charge at Vgs=5V | $V_{DD} = 15 \text{ V}, I_D = 14.5 \text{ A},$ | | 25 | 35 | nC |
| Q_{gs} | Gate-Source Charge | | | 7 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 8 | | nC |

Electrical Characteristics

T_A = 25°C unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|-----------------|--|--|-----|------------|-----|-------|
| Drain-Sc | Drain–Source Diode Characteristics and Maximum Ratings | | | | | |
| V_{SD} | Drain–Source Diode Forward Voltage | $V_{GS} = 0 \text{ V}, I_S = 3.5 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 7 \text{ A}$ (Note 2) | | 0.4 0.5 | 0.7 | V |
| t _{rr} | Diode Reverse Recovery Time | I _F = 14.5A, | | 27 | | nS |
| I _{RM} | Diode Reverse Recovery Current | $d_{iF}/d_t = 300 \text{ A/}\mu\text{s} \qquad (Note 3)$ | | 1.9 | | Α |
| Q _{rr} | Diode Reverse Recovery Charge | | | 26 | | nC |

Notes

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8JC} is guaranteed by design while R_{8CA} is determined by the user's board design.



a) 50°/W when mounted on a 1 in² pad of 2 oz copper



b) 105°/W when mounted on a .04 in² pad of 2 oz copper



Typical Characteristics

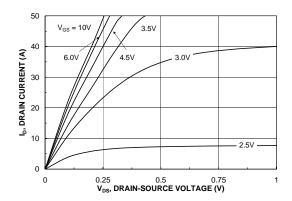


Figure 1. On-Region Characteristics.

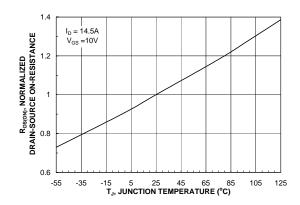


Figure 3. On-Resistance Variation with Temperature.

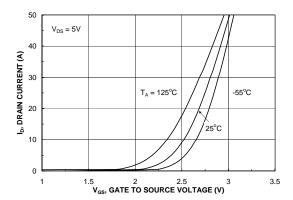


Figure 5. Transfer Characteristics.

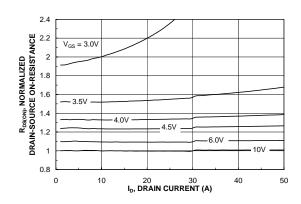


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

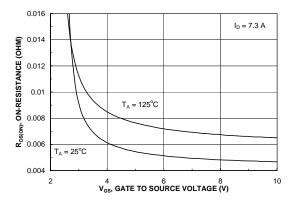


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

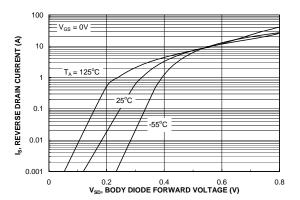
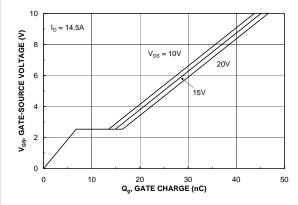


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



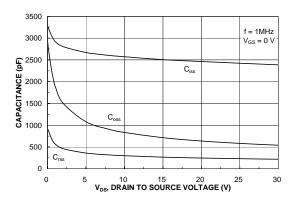
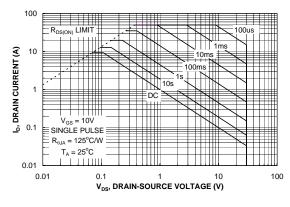


Figure 7. Gate Charge Characteristics.





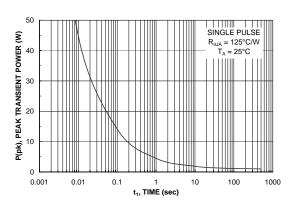


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

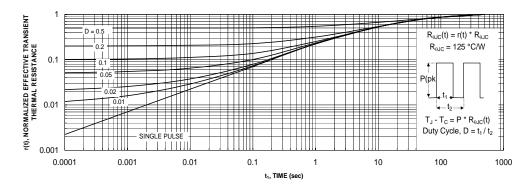


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6676AS.

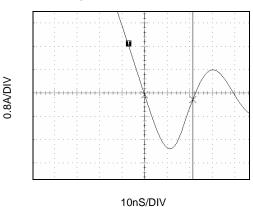


Figure 12. FDS6676AS SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6676).

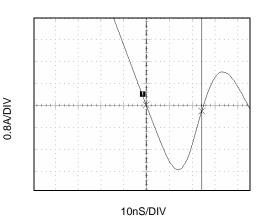


Figure 13. Non-SyncFET (FDS6676) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

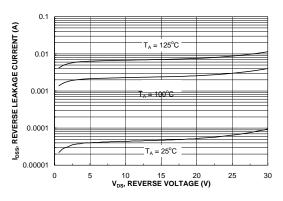
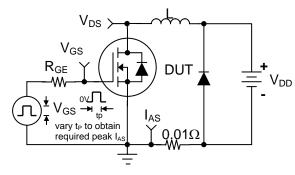


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

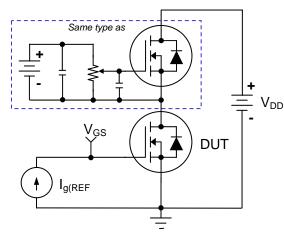
Typical Characteristics



BV_{DSS}
V_{DS}
V_{DD}
V_{DD}

Figure 15. Unclamped Inductive Load Test Circuit

Figure 16. Unclamped Inductive Waveforms



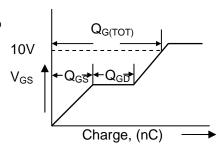
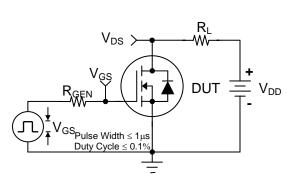


Figure 17. Gate Charge Test Circuit

Figure 18. Gate Charge Waveform



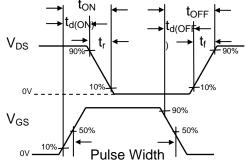


Figure 19. Switching Time Test Circuit

Figure 20. Switching Time Waveforms





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